

P-Channel Enhancement Mode MOSFET

Features

• -20V/-2.8A,

$$R_{DS(ON)} = 72 m\Omega(typ.)$$
 @ $V_{GS} = -10V$
 $R_{DS(ON)} = 98 m\Omega(typ.)$ @ $V_{GS} = -4.5V$

- Super High Dense Cell Design
- Reliable and Rugged
- Lead Free Available (RoHS Compliant)

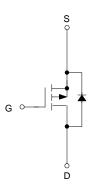
Applications

Power Management in Notebook Computer,
 Portable Equipment and Battery Powered
 Systems

Pin Description

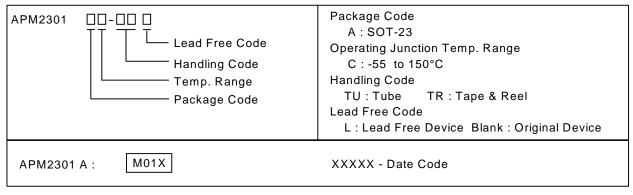


Top View of SOT-23



P-Channel MOSFET

Ordering and Marking Information



Note: ANPEC lead-free products contain molding compounds/die attach materials and 100% matte in plate termination finish; which are fully compliant with RoHS and compatible with both SnPb and lead-free soldiering operations. ANPEC lead-free products meet or exceed the lead-free requirements of IPC/JEDEC J STD-020C for MSL classification at lead-free peak reflow temperature.

ANPEC reserves the right to make changes to improve reliability or manufacturability without notice, and advise customers to obtain the latest version of relevant information to verify before placing orders.



Absolute Maximum Ratings ($T_A = 25$ °C unless otherwise noted)

Symbol	Parameter	Rating	Unit	
V_{DSS}	Drain-Source Voltage		-20	M
V _{GSS}	Gate-Source Voltage		±16	V
l _D *	Continuous Drain Current	101	-2.8	А
I _{DM} *	V _{GS} =-10V 300μs Pulsed Drain Current		-10	A
l _S *	Diode Continuous Forward Current	-1	А	
TJ	Maximum Junction Temperature	150	°C	
T _{STG}	Storage Temperature Range	-55 to 150)	
D *	T _A =25°		0.83	W
P _D *	Maximum Power Dissipation	T _A =100°C	0.3	VV
R _{θJA} *	Thermal Resistance-Junction to Ambier	150	°C/W	

Note:

Electrical Characteristics $(T_A = 25^{\circ}C \text{ unless otherwise noted})$

Symbol	Parameter	Test Condition	A	PM2301	Unit	
Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Oilit
Static Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _{DS} =-250μA	-20			>
I	Zero Gate Voltage Drain Current	V _{DS} =-16V, V _{GS} =0V			-1	μΑ
I _{DSS}	Zero Gate Voltage Drain Guirent	T _J =85°C			-30 ^μ	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_{DS}=-250\mu A$	-0.55	-0.7	-1.5	V
I _{GSS}	Gate Leakage Current	V _{GS} =±16V, V _{DS} =0V			±100	nA
D a	Drain-Source On-state Resistance	V _{GS} =-10V, I _{DS} =-2.8A		72	85	m 0
R _{DS(ON)} a	Main-Source On-State Resistance	V _{GS} =-4.5V, I _{DS} =-2.5A		98	110	mΩ
V_{SD}^{a}	Diode Forward Voltage	I _{SD} =-1.25A, V _{GS} =0V		-0.7	-1.3	V
Gate Char	ge Characteristics ^b					
Q_g	Total Gate Charge			7.6	10	
Q _{gs}	Gate-Source Charge]V _{DS} =-10V, V _{GS} =-4.5V, I _{DS} =-2.8A		3.2		nC
Q_{gd}	Gate-Drain Charge	1.03		2		

^{*}Surface Mounted on $1in^2$ pad area, $t \le 10$ sec.



Electrical Characteristics (Cont.) $(T_A = 25^{\circ}C \text{ unless otherwise noted})$

Cumbal	Parameter	Toot Condition	Test Condition APM2301A			Unit			
Symbol	Parameter	rest Condition	Min. Typ. Max.		Max.	Unit			
Dynamic	Dynamic Characteristics ^b								
R_G	Gate Resistance	V _{GS} =0V,V _{DS} =0V,F=1MHz		11		Ω			
C _{iss}	Input Capacitance	V _{GS} =0V,		450					
C _{oss}	Output Capacitance	V _{DS} =-15V,		100		pF			
C_{rss}	Reverse Transfer Capacitance	Frequency=1.0MHz		60					
t _{d(ON)}	Turn-on Delay Time			11	22				
T _r	Turn-on Rise Time	V_{DD} =-10V, R_L =10 Ω ,		32	55				
t _{d(OFF)}	Turn-off Delay Time	I_{DS} =-1A, V_{GEN} =-4.5V, R_G =6 Ω		38	68	ns			
T _f	Turn-off Fall Time			32	55				

Notes:

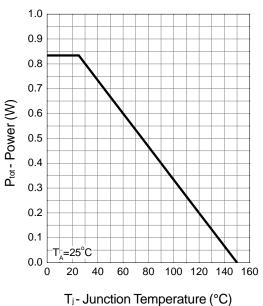
a : Pulse test ; pulse width≤300µs, duty cycle≤2%.

b : Guaranteed by design, not subject to production testing.

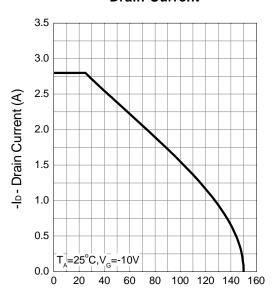


Typical Characteristics

Power Dissipation

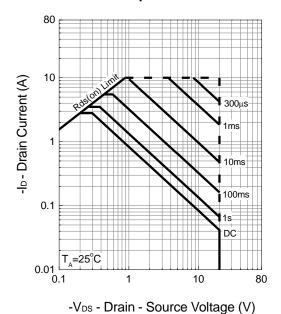


Drain Current

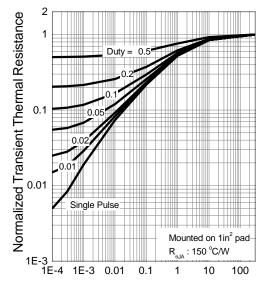


T_i - Junction Temperature (°C)

Safe Operation Area



Thermal Transient Impedance

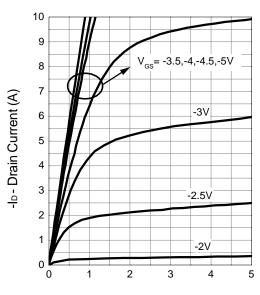


Square Wave Pulse Duration (sec)



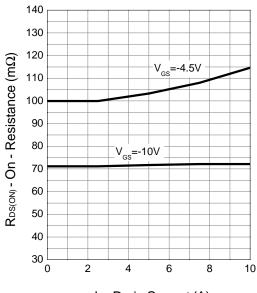
Typical Characteristics (Cont.)





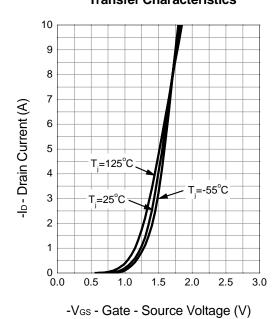
-V_{DS} - Drain - Source Voltage (V)

Drain-Source On Resistance

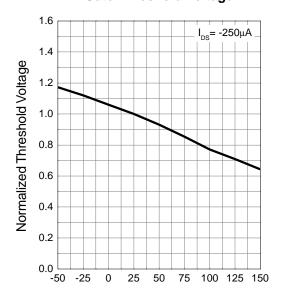


-ID - Drain Current (A)

Transfer Characteristics



Gate Threshold Voltage

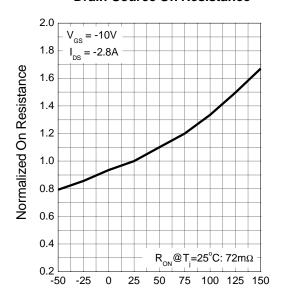


T_j - Junction Temperature (°C)



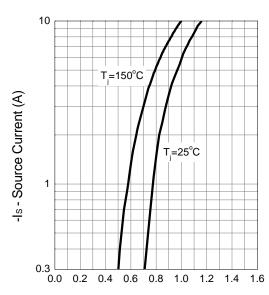
Typical Characteristics (Cont.)

Drain-Source On Resistance



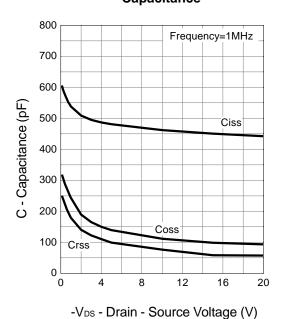
T_j - Junction Temperature (°C)

Source-Drain Diode Forward

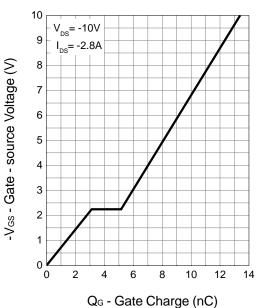


-Vsp - Source - Drain Voltage (V)

Capacitance



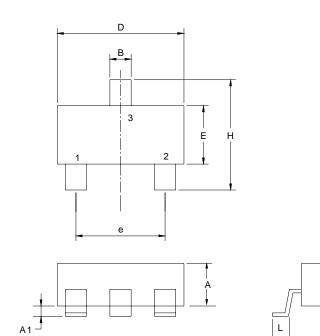
Gate Charge





Packaging Information

SOT-23



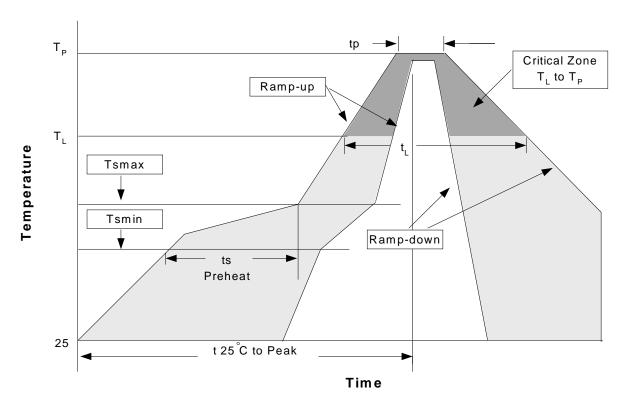
Dim	Millim	neters	Inch	ies
	Min.	Max.	Min.	Max.
Α	1.00	1.30	0.039	0.051
A1	0.00	0.10	0.000	0.004
В	0.35	0.51	0.014	0.020
С	0.10	0.25	0.004	0.010
D	2.70	3.10	0.106	0.122
Е	1.40	1.80	0.055	0.071
е	1.90/2.	1 BSC.	0.075/0.083 BSC.	
Н	2.40	3.00	0.094	0.118
L	0.37		0.015	



Physical Specifications

Terminal Material	Solder-Plated Copper (Solder Material : 90/10 or 63/37 SnPb), 100%Sn
Lead Solderability	Meets EIA Specification RSI86-91, ANSI/J-STD-002 Category 3.

Reflow Condition (IR/Convection or VPR Reflow)



Classification Reflow Profiles

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Average ramp-up rate (T _L to T _P)	3°C/second max.	3°C/second max.
Preheat - Temperature Min (Tsmin) - Temperature Max (Tsmax) - Time (min to max) (ts)	100°C 150°C 60-120 seconds	150°C 200°C 60-180 seconds
Time maintained above: - Temperature (T _L) - Time (t _L)	183°C 60-150 seconds	217°C 60-150 seconds
Peak/Classificatioon Temperature (Tp)	See table 1	See table 2
Time within 5°C of actual Peak Temperature (tp)	10-30 seconds	20-40 seconds
Ramp-down Rate	6°C/second max.	6°C/second max.
Time 25°C to Peak Temperature	6 minutes max.	8 minutes max.

Notes: All temperatures refer to topside of the package .Measured on the body surface.



Classification Reflow Profiles(Cont.)

Table 1. SnPb Entectic Process - Package Peak Reflow Temperatures

Package Thickness	Volume mm³ <350	Volume mm³ ≥350
<2.5 mm	240 +0/-5°C	225 +0/-5°C
≥2.5 mm	225 +0/-5°C	225 +0/-5°C

Table 2. Pb-free Process – Package Classification Reflow Temperatures

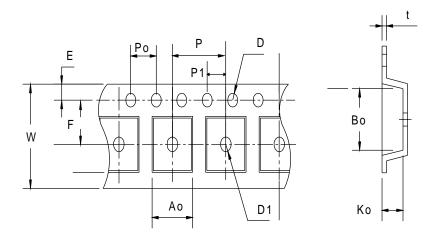
Package Thickness	Volume mm ³ <350	Volume mm ³ 350-2000	Volume mm³ >2000
<1.6 mm	260 +0°C*	260 +0°C*	260 +0°C*
1.6 mm – 2.5 mm	260 +0°C*	250 +0°C*	245 +0°C*
≥2.5 mm	250 +0°C*	245 +0°C*	245 +0°C*

^{*}Tolerance: The device manufacturer/supplier **shall** assure process compatibility up to and including the stated classification temperature (this means Peak reflow temperature +0°C. For example 260°C+0°C) at the rated MSL level.

Reliability Test Program

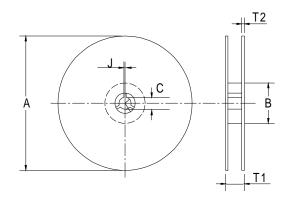
Test item	Method	Description
SOLDERABILITY	MIL-STD-883D-2003	245°C,5 SEC
HOLT	MIL-STD 883D-1005.7	1000 Hrs Bias @ 125°C
PCT	JESD-22-B, A102	168 Hrs, 100% RH, 121°C
TST	MIL-STD 883D-1011.9	-65°C ~ 150°C, 200 Cycles

Carrier Tape & Reel Dimensions





Carrier Tape & Reel Dimensions



Application	Α	В	C	J	T1	T2	W	Р	E
	178±1	60 ± 1.0	12.0	2.5 ± 0.15	9.0 ± 0.5	1.4	8.0+ 0.3 - 0.3	4.0	1.75
SOT-23	F	D	D1	Po	P1	Ao	Во	Ko	t
	3.5 ± 0.05	1.5 +0.1	₽.1MIN	4.0	2.0 ± 0.05	3.1	3.0	1.3	0.2±0.03

(mm)

Cover Tape Dimensions

Application	Carrier Width	Cover Tape Width	Devices Per Reel
SOT- 23	8	5.3	3000

Customer Service

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